

### ● General Description

The AGM405D combines advanced trench MOSFET technology with a low resistance package to provide extremely low  $R_{DS(ON)}$ . This device is ideal for load switch and battery protection applications.

### Product Summary

BVDSS	RDS(on)	ID
40V	5.3mΩ	72A

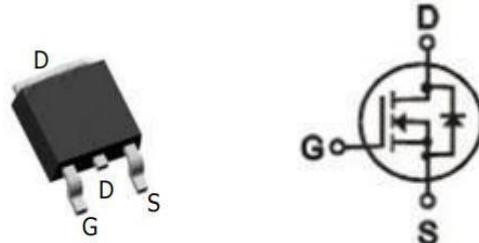
### ● Features

- Advance high cell density Trench technology
- Low  $R_{DS(ON)}$  to minimize conductive loss
- Low Gate Charge for fast switching
- Low Thermal resistance

### ● Application

- MB/VGA Vcore
- SMPS 2<sup>nd</sup> Synchronous Rectifier
- POL application
- BLDC Motor driver

### TO-252 Pin Configuration



### Package Marking and Ordering Information

Device Marking	Device	Device Package	Reel Size	Tape width	Quantity
AGM405D	AGM405D	TO-252	325mm	16mm	2500

Table 1. Absolute Maximum Ratings (TA=25°C)

Symbol	Parameter	Value	Unit
VDS	Drain-Source Voltage (VGS=0V)	40	V
VGS	Gate-Source Voltage (VDS=0V)	±20	V
ID	Drain Current-Continuous(Tc=25°C) <b>(Note 1)</b>	72	A
	Drain Current-Continuous(Tc=100°C)	52	A
IDM (pulse)	Drain Current-Continuous@ Current-Pulsed <b>(Note 2)</b>	220	A
PD	Maximum Power Dissipation(Tc=25°C)	64	W
	Maximum Power Dissipation(Tc=125°C)	--	W
EAS	Avalanche energy <b>(Note 3)</b>	--	mJ
TJ,TSTG	Operating Junction and Storage Temperature Range	-55 To 175	°C

Table 2. Thermal Characteristic

Symbol	Parameter	Typ	Max	Unit
R <sub>θJA</sub>	Thermal Resistance Junction-ambient (Steady State) <sup>1</sup>	---	50	°C/W
R <sub>θJC</sub>	Thermal Resistance Junction-Case <sup>1</sup>	---	2.4	°C/W

**Table 3. Electrical Characteristics (TA=25°C unless otherwise noted)**

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
<b>On/Off States</b>						
BVDSS	Drain-Source Breakdown Voltage	VGS=0V ID=250μA	40	--	--	V
IDSS	Zero Gate Voltage Drain Current	VDS=40V, VGS=0V	--	--	1.0	μA
IGSS	Gate-Body Leakage Current	VGS=±20V, VDS=0V	--	--	±100	nA
VGS(th)	Gate Threshold Voltage	VDS=VGS, ID=250μA	1.0	1.5	2.0	V
gFS	Forward Transconductance	VDS=5V, ID=20A	10	--	--	S
RDS(on)	Drain-Source On-State Resistance	VGS=10V, ID=30A	--	5.3	7.5	mΩ
		VGS=4.5V, ID=20A	--	9	11	mΩ
<b>Dynamic Characteristics</b>						
Ciss	Input Capacitance	VDS=20V, VGS=0V, F=1MHZ	--	1820	--	pF
Coss	Output Capacitance		--	285	--	pF
Crss	Reverse Transfer Capacitance		--	191	--	pF
Rg	Gate resistance	VGS=0V, VDS=-0V, f=1.0MHz	--	--	--	Ω
<b>Switching Times</b>						
td(on)	Turn-on Delay Time	VGS=10V, VDS=20V ID=30A, RGEN=3Ω	--	6.5	--	nS
tr	Turn-on Rise Time		--	17	--	nS
td(off)	Turn-Off Delay Time		--	30	--	nS
tf	Turn-Off Fall Time		--	16	--	nS
Qg	Total Gate Charge	VGS=10V, VDS=20V, ID=30A	--	29	--	nC
Qgs	Gate-Source Charge		--	4.5	--	nC
Qgd	Gate-Drain Charge		--	6.4	--	nC
<b>Source-Drain Diode Characteristics</b>						
ISD	Source-Drain Current(Body Diode)		--	--	72	A
VSD	Forward on Voltage	VGS=0V, IS=30A	--	--	1.2	V
trr	Reverse Recovery Time	IF=20A, dl/dt=100A/μs, TJ=25°C	--	26	--	ns
Qrr	Reverse Recovery Charge		--	22	--	nc

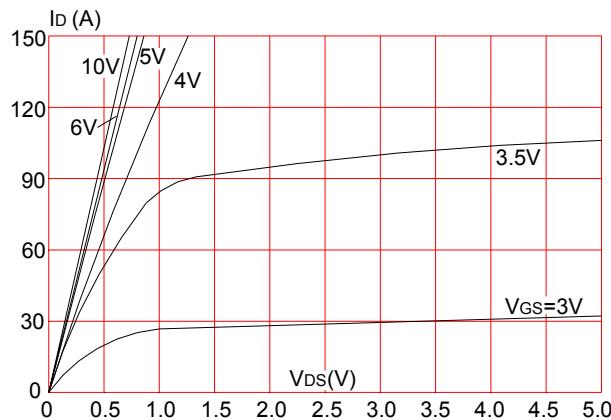
Notes 1.The maximum current rating is package limited.

Notes 2.Repetitive Rating: Pulse width limited by maximum junction temperature

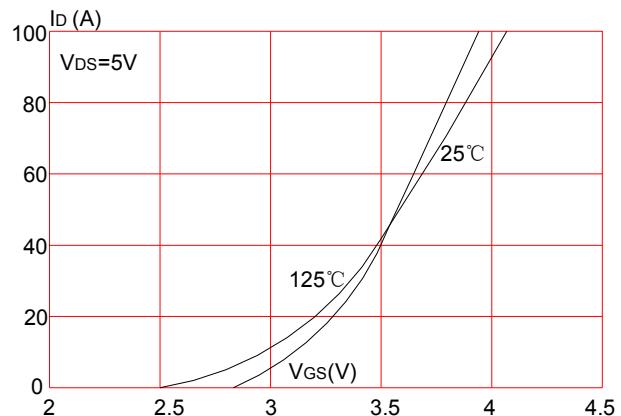
Notes 3.Pulse Test: Pulse Width≤300μs, Duty Cycle≤0.5%

## Typical Performance Characteristics

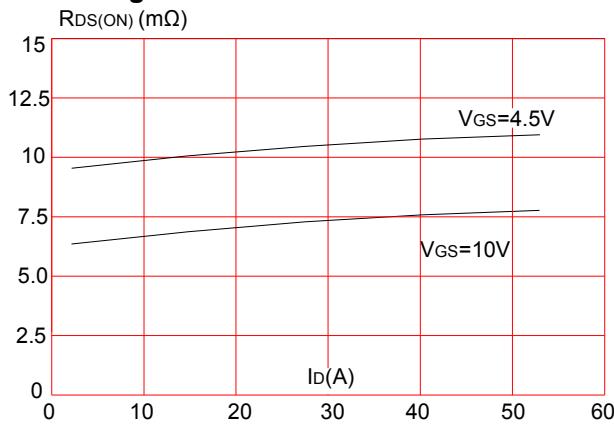
**Figure1:** Output Characteristics



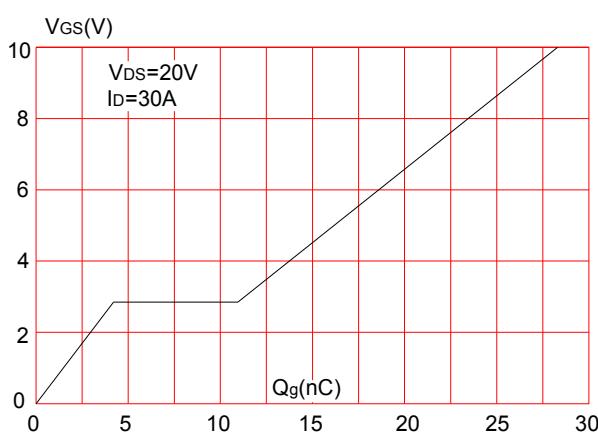
**Figure 2:** Typical Transfer Characteristics



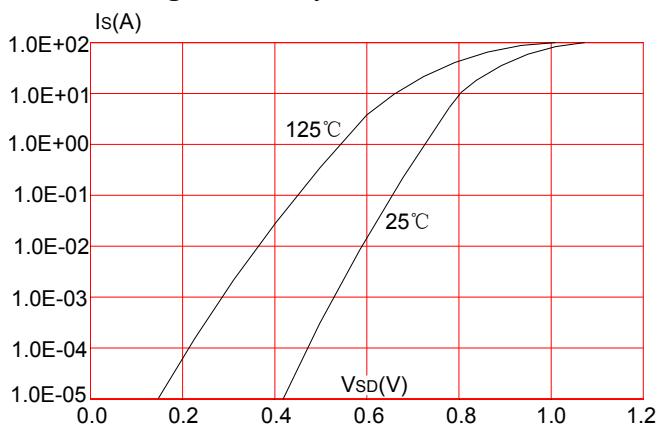
**Figure 3:** On-resistance vs. Drain Current



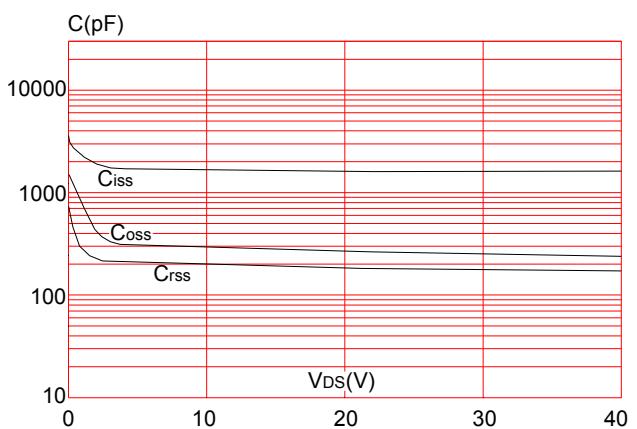
**Figure 5:** Gate Charge Characteristics



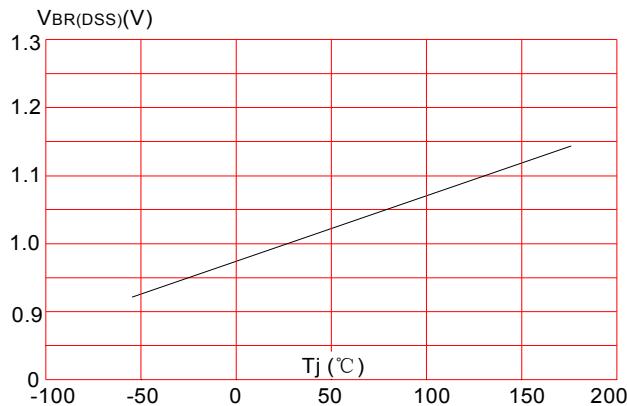
**Figure 4:** Body Diode Characteristics



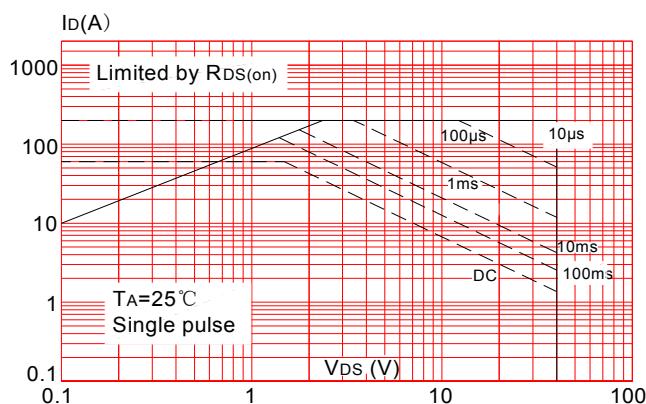
**Figure 6:** Capacitance Characteristics



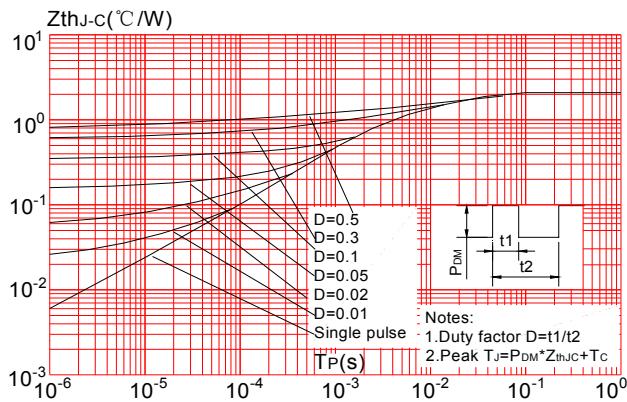
**Figure 7:** Normalized Breakdown Voltage vs. Junction Temperature



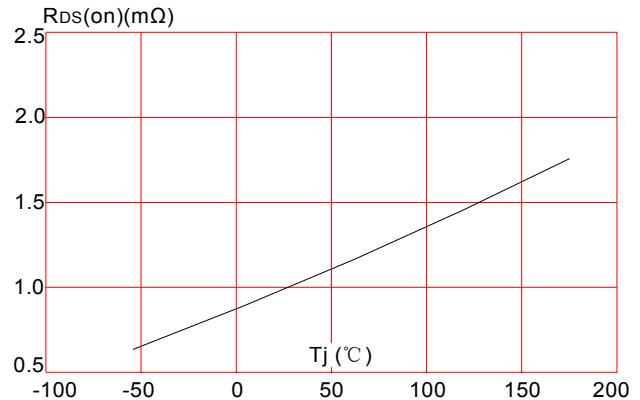
**Figure 9:** Maximum Safe Operating Area



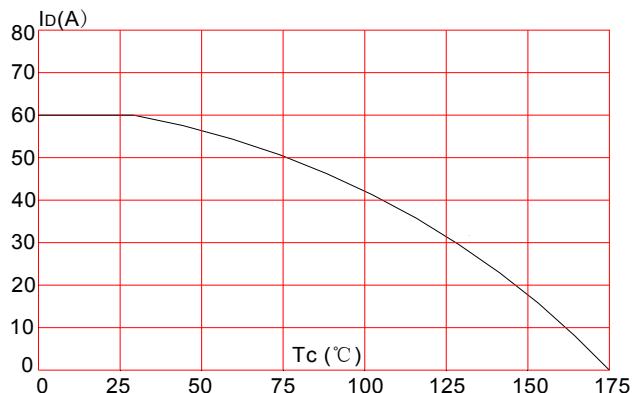
**Figure 11:** Maximum Effective Transient Thermal Impedance, Junction-to-Case (TO-251S, TO-252)



**Figure 8:** Normalized on Resistance vs. Junction Temperature



**Figure 10:** Maximum Continuous Drain Current vs. Case Temperature



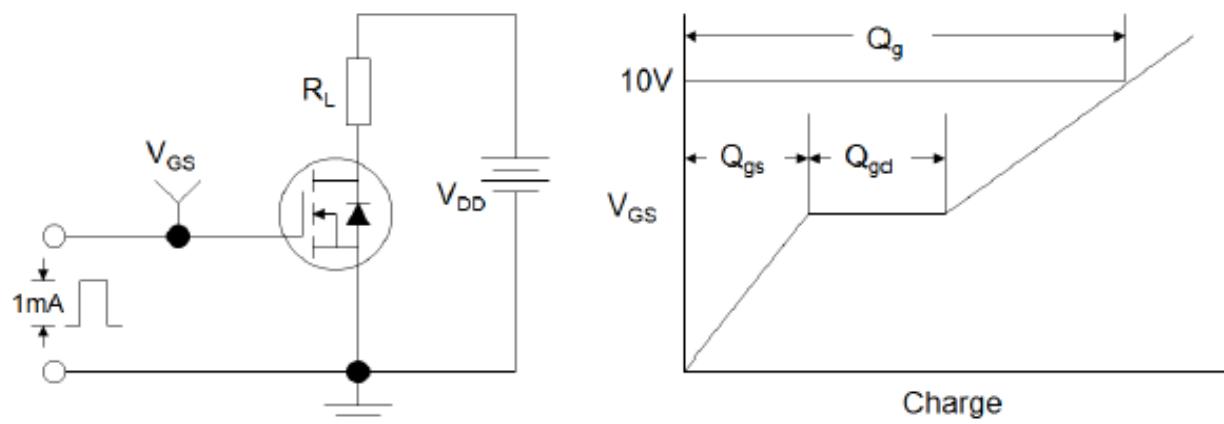


Figure1:Gate Charge Test Circuit &amp; Waveform

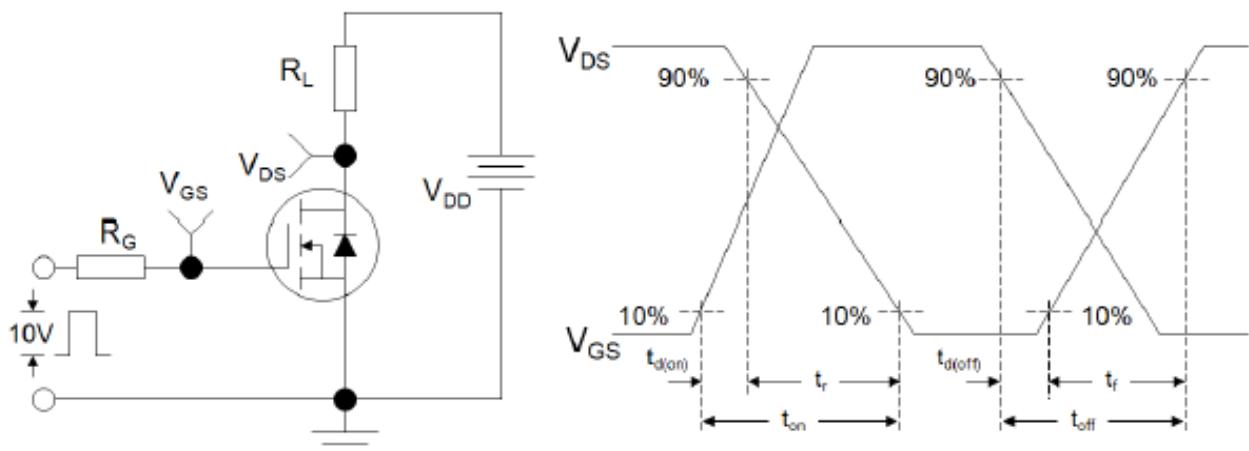


Figure 2: Resistive Switching Test Circuit &amp; Waveforms

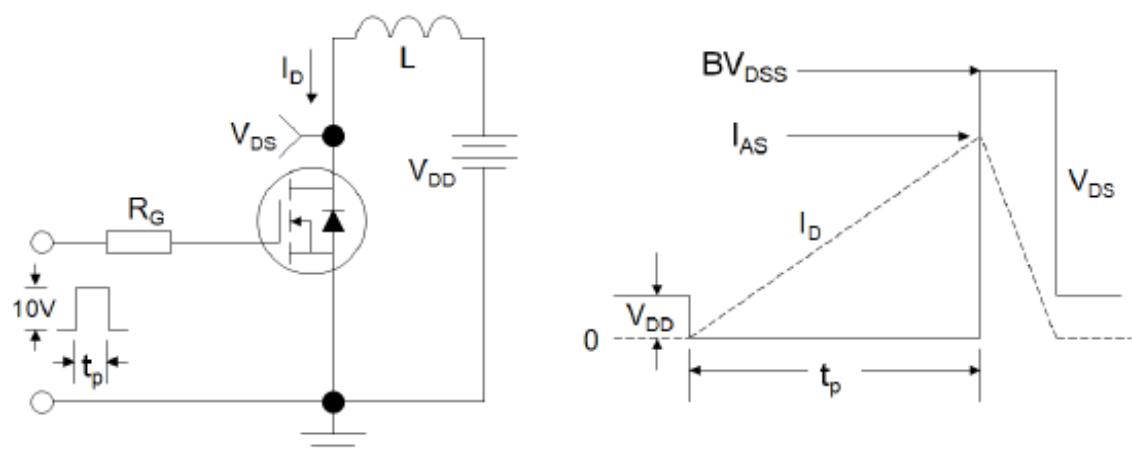
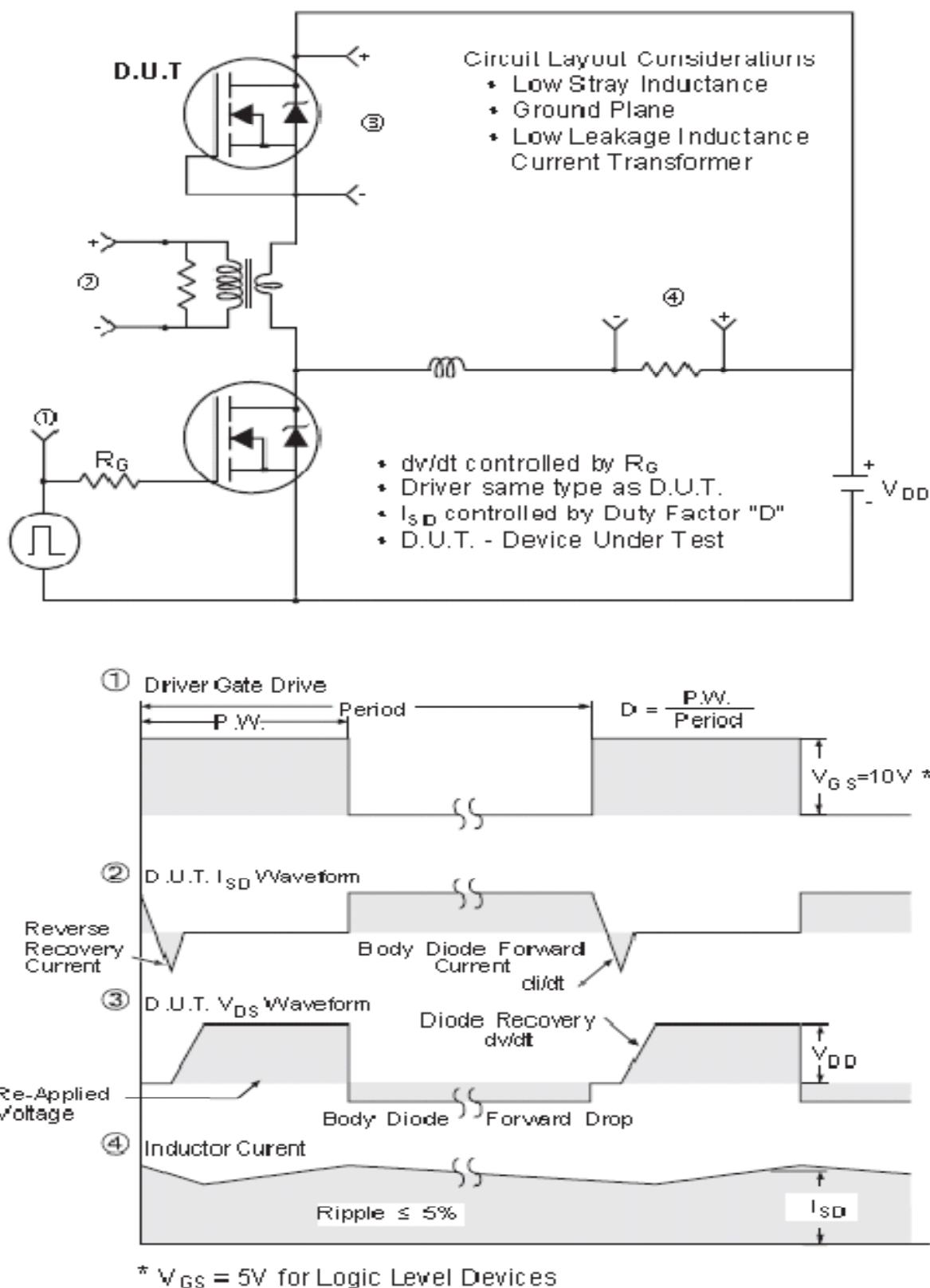


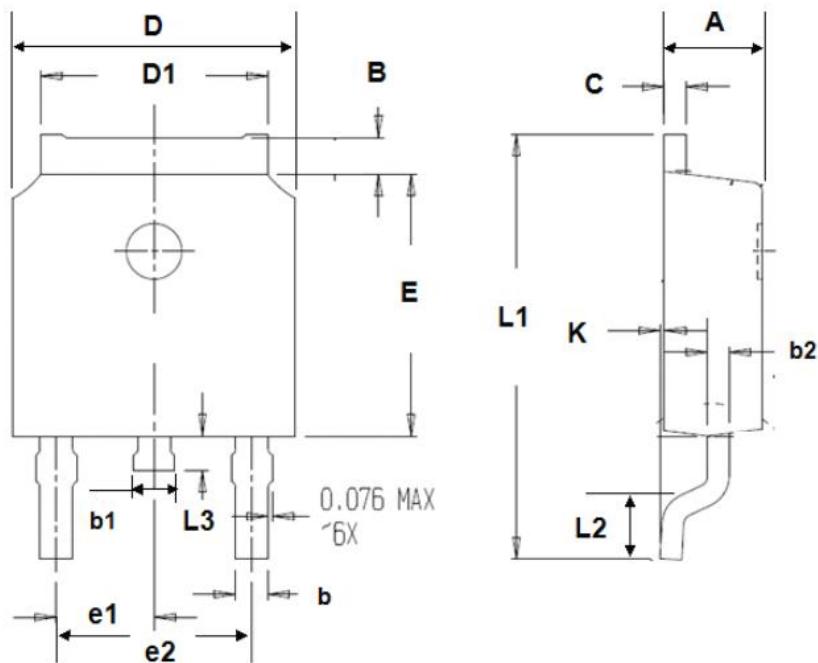
Figure 3:Unclamped Inductive Switching Test Circuit &amp; Waveforms



**Figure 4:Peak Diode Recovery dv/dt Test Circuit & Waveforms (For N-channel)**

## •Dimensions

SYMBOL	min	max	SYMBOL	min	max
A	2.10	2.50	B	0.85	1.25
b	0.50	0.80	b1	0.50	0.90
b2	0.45	0.70	C	0.45	0.70
D	6.30	6.75	D1	5.10	5.50
E	5.30	6.30	e1	2.25	2.35
L1	9.20	10.60	e2	4.45	4.75
L2	0.90	1.75	L3	0.60	1.10
K	0.00	0.23			



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